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Introduction

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Template for comments and secretariat observations

Date: xx/xx/20xx	Document: ISO/DIS xxxx
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1	2	(3)	4	5	(6)	7
MB	Clause No./ Subclause No./Annex (e.g. 3.1)	Paragraph/ Figure/Table/Note	Type of comment	Comment (justification for change) by the MB	Proposed change by the MB	Secretariat observations on each comment submitted
	3.1	Definition 1	ed	Definition is ambiguous and needs clarifying.	Amend to read '...so that the mains connector to which no connection...'	
	6.4	Paragraph 2	te	The use of the UV photometer as an alternative cannot be supported as serious problems have been encountered in its use in the UK.	Delete reference to UV photometer.	



86/659/CD

COMMITTEE DRAFT (CD)

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SUPERSEDES DOCUMENTS:
86/634/NP, 86/648/RVN

IEC TC 86 : FIBRE OPTICS	
SECRETARIAT: United States of America	SECRETARY: Mr Peter Pondillo
OF INTEREST TO THE FOLLOWING COMMITTEES: SC 86A,SC 86B,SC 86C	HORIZONTAL FUNCTION(S):
ASPECTS CONCERNED:	

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TITLE:

Optical circuit boards – Part 2-6: Basic test and measurement procedures – Near field pattern analysis of multimode optical waveguides with rectangular core(s) using encircled flux methodology

NOTE FROM TC/SC OFFICERS:

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

OPTICAL CIRCUIT BOARDS –

Part 2-6: Basic test and measurement procedures – Near field pattern analysis of multimode optical waveguides with rectangular core(s) using encircled flux methodology

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The text of this International Standard is based on the following documents:

Draft	Report on voting
86/XX/FDIS	86/XX/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.